



YOUSHANG SEMICONDUCTOR

设计研发新型功率器件

各类小信号开关

中低压及高压大电流等场效应管

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企业微信二维码



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Product Summary

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D $T_A = +25^\circ\text{C}$
35V	$35\text{m}\Omega @ V_{GS} = 10\text{V}$	13A
-35V	$45\text{m}\Omega @ V_{GS} = -10\text{V}$	-12A

Description

This new generation MOSFET has been designed to minimize the on-state resistance ($R_{DS(on)}$) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

Applications

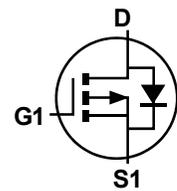
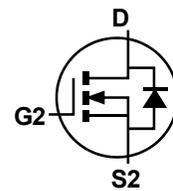
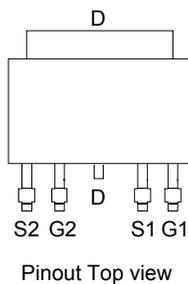
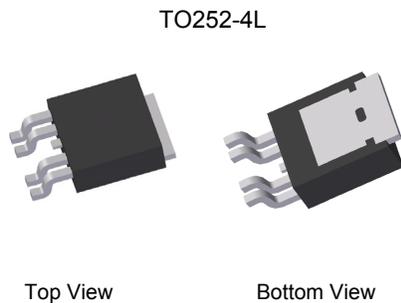
- Backlighting
- DC-DC Converters
- Power management functions

Features and Benefits

- 0.6mm profile – ideal for low profile applications
- PCB footprint of 4mm^2
- Low Gate Threshold Voltage

Mechanical Data

- Case: TO252-4L
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections Indicator: See diagram
- Terminals: Finish – Matte Tin annealed over Copper leadframe. Solderable per MIL-STD-202, Method 208 (e3)
- Weight: 0.328 grams (approximate)



Maximum Ratings – N-CHANNEL, Q1 (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic			Symbol	Value	Unit
Drain-Source Voltage			V_{DSS}	35	V
Gate-Source Voltage			V_{GSS}	± 20	V
Continuous Drain Current (Note 5) $V_{GS} = 10\text{V}$	Steady State	$T_A = +25^\circ\text{C}$	I_D	5.3	A
		$T_A = +70^\circ\text{C}$		4.2	
Continuous Drain Current (Note 6) $V_{GS} = 10\text{V}$	Steady State	$T_A = +25^\circ\text{C}$	I_D	8.6	A
		$T_A = +70^\circ\text{C}$		6.8	
Continuous Drain Current (Note 6) $V_{GS} = 10\text{V}$	$t \leq 10\text{s}$	$T_A = +25^\circ\text{C}$	I_D	13	A
		$T_A = +70^\circ\text{C}$		11	
Continuous Drain Current (Note 6) $V_{GS} = 4.5\text{V}$	Steady State	$T_A = +25^\circ\text{C}$	I_D	6.3	A
		$T_A = +70^\circ\text{C}$		5.0	
Continuous Drain Current (Note 6) $V_{GS} = 4.5\text{V}$	$t \leq 10\text{s}$	$T_A = +25^\circ\text{C}$	I_D	9.3	A
		$T_A = +70^\circ\text{C}$		7.4	
Pulsed Drain Current (Note 7)			I_{DM}	50	A

Maximum Ratings – P-CHANNEL, Q2 (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic			Symbol	Value	Unit
Drain-Source Voltage			V_{DSS}	-35	V
Gate-Source Voltage			V_{GSS}	± 20	V
Continuous Drain Current (Note 5) $V_{GS} = -10\text{V}$	Steady State	$T_A = +25^\circ\text{C}$	I_D	-5.0	A
		$T_A = +70^\circ\text{C}$		-3.8	
Continuous Drain Current (Note 6) $V_{GS} = -10\text{V}$	Steady State	$T_A = +25^\circ\text{C}$	I_D	-7.8	A
		$T_A = +70^\circ\text{C}$		-6.2	
Continuous Drain Current (Note 6) $V_{GS} = -10\text{V}$	$t \leq 10\text{s}$	$T_A = +25^\circ\text{C}$	I_D	-12	A
		$T_A = +70^\circ\text{C}$		-10	
Continuous Drain Current (Note 6) $V_{GS} = -4.5\text{V}$	Steady State	$T_A = +25^\circ\text{C}$	I_D	-6.5	A
		$T_A = +70^\circ\text{C}$		-5.2	
Continuous Drain Current (Note 6) $V_{GS} = -4.5\text{V}$	$t \leq 10\text{s}$	$T_A = +25^\circ\text{C}$	I_D	-9.6	A
		$T_A = +70^\circ\text{C}$		-7.7	
Pulsed Drain Current (Note 7)			I_{DM}	-50	A

Thermal Characteristics

Characteristic	Symbol	Value	Unit
Power Dissipation (Note 5)	P_D	1.54	W
Thermal Resistance, Junction to Ambient @ $T_A = +25^\circ\text{C}$ (Note 5)	$R_{\theta JA}$	81.3	$^\circ\text{C/W}$
Power Dissipation (Note 6)	P_D	4.1	W
Thermal Resistance, Junction to Ambient @ $T_A = +25^\circ\text{C}$ (Note 6)	$R_{\theta JA}$	30.8	$^\circ\text{C/W}$
Power Dissipation (Note 6) $t \leq 10\text{s}$	P_D	8.9	W
Thermal Resistance, Junction to Ambient @ $T_A = +25^\circ\text{C}$ (Note 5) $t \leq 10\text{s}$	$R_{\theta JA}$	14	$^\circ\text{C/W}$
Operating and Storage Temperature Range	T_J, T_{STG}	-55 to +150	$^\circ\text{C}$

- Notes:
- Device mounted on FR-4 PC board, with minimum recommended pad layout, single sided.
 - Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate
 - I_{AS} and E_{AS} rating are based on low frequency and duty cycles to keep $T_J = +25^\circ\text{C}$
 - Short duration pulse test used to minimize self-heating effect.
 - Guaranteed by design. Not subject to product testing.

Electrical Characteristics – N-CHANNEL, Q1 (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

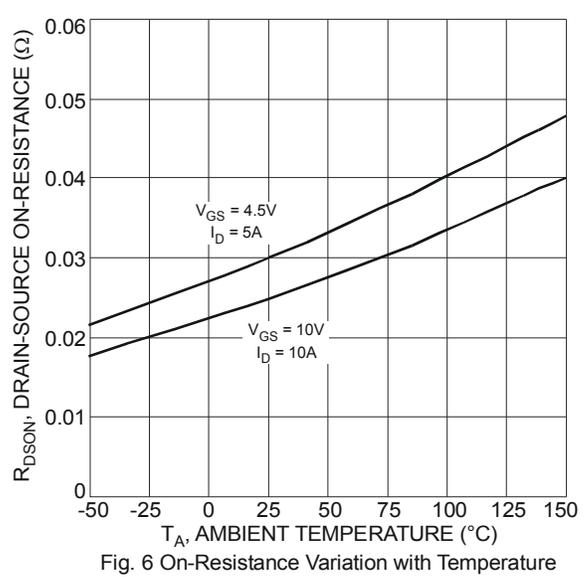
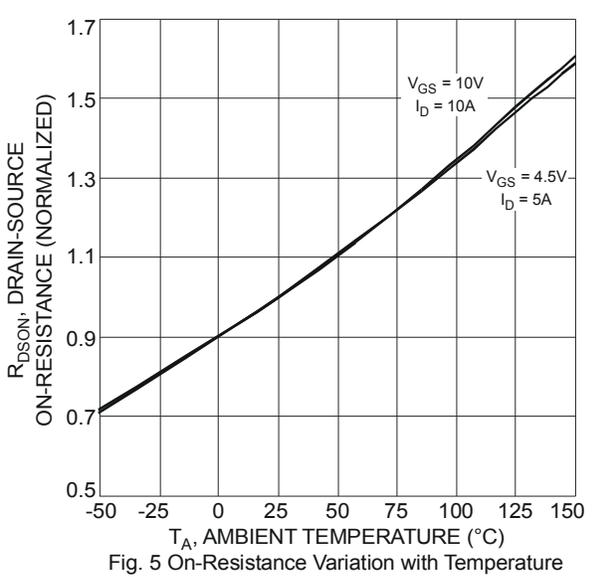
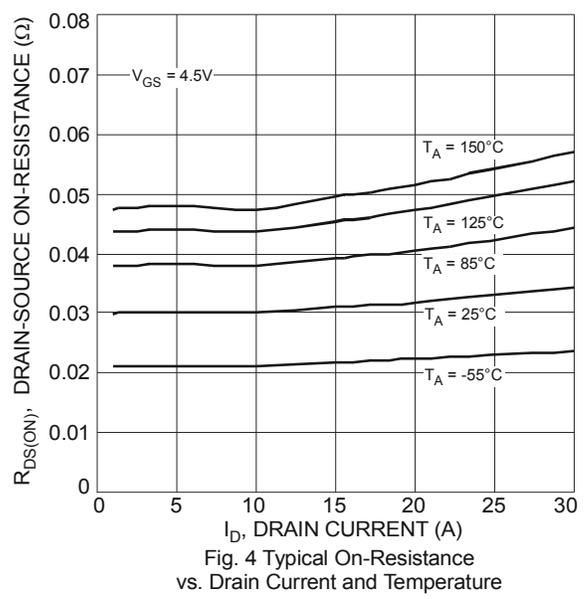
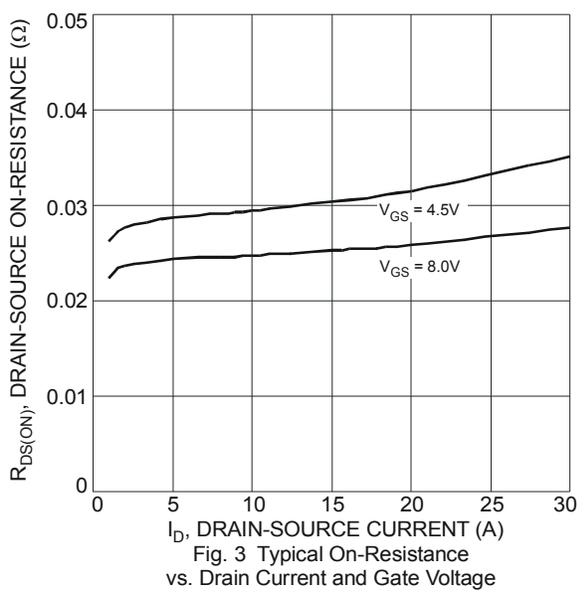
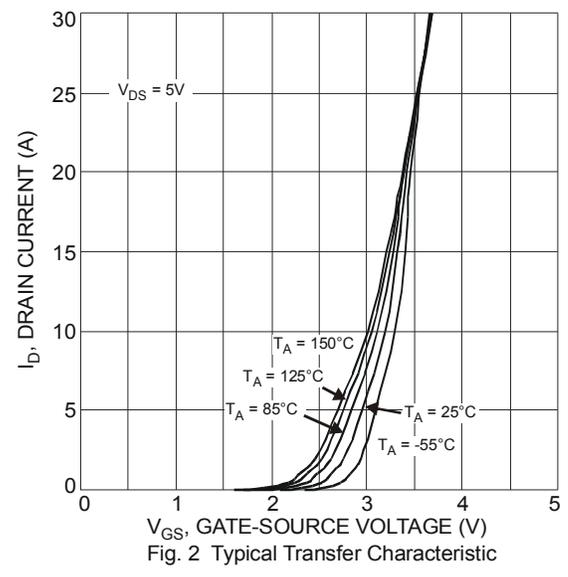
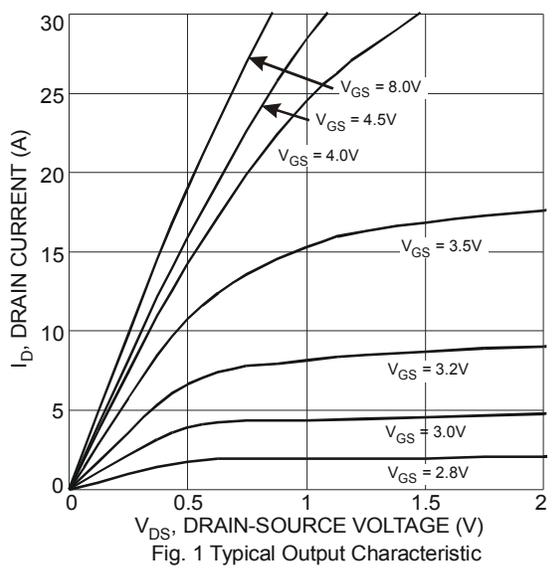
Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 8)						
Drain-Source Breakdown Voltage	BV_{DSS}	35	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
Zero Gate Voltage Drain Current $T_J = +25^\circ\text{C}$	I_{DSS}	—	—	1.0	μA	$V_{DS} = 35V, V_{GS} = 0V$
Gate-Source Leakage	I_{GSS}	—	—	± 100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 8)						
Gate Threshold Voltage	$V_{GS(th)}$	1.0	—	3.0	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
Static Drain-Source On-Resistance	$R_{DS(on)}$	—	25 50	35 65	m Ω	$V_{GS} = 10V, I_D = 8A$ $V_{GS} = 4.5V, I_D = 6A$
Forward Transfer Admittance	$ Y_{fs} $	—	4.5	—	S	$V_{DS} = 10V, I_D = 8A$
Diode Forward Voltage	V_{SD}	—	—	1.2	V	$V_{GS} = 0V, I_S = 8A$
DYNAMIC CHARACTERISTICS (Note 9)						
Input Capacitance	C_{iss}	—	850	—	pF	$V_{DS} = 25V, V_{GS} = 0V,$ $f = 1.0\text{MHz}$
Output Capacitance	C_{oss}	—	64.7	—	pF	
Reverse Transfer Capacitance	C_{rss}	—	51.9	—	pF	
Gate Resistance	R_g	—	1.6	—	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1\text{MHz}$
Total Gate Charge ($V_{GS} = 10V$)	Q_g	—	18.7	—	nC	$V_{GS} = 10V, V_{DS} = 28V, I_D = 8A$ $V_{GS} = 4.5V, V_{DS} = 28V,$ $I_D = 8A$
Total Gate Charge ($V_{GS} = 4.5V$)	Q_g	—	8.8	—		
Gate-Source Charge	Q_{gs}	—	2.6	—		
Gate-Drain Charge	Q_{gd}	—	2.1	—		
Turn-On Delay Time	$t_{D(on)}$	—	5.4	—	ns	$V_{DS} = 18V, V_{GS} = 10V,$ $R_L = 18\Omega, R_G = 3.3\Omega,$ $I_D = 1A$
Turn-On Rise Time	t_r	—	2.8	—	ns	
Turn-Off Delay Time	$t_{D(off)}$	—	33.2	—	ns	
Turn-Off Fall Time	t_f	—	35.6	—	ns	

Electrical Characteristics – P-CHANNEL, Q2 (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 8)						
Drain-Source Breakdown Voltage	BV_{DSS}	-35	—	—	V	$V_{GS} = 0V, I_D = -250\mu A$
Zero Gate Voltage Drain Current $T_J = 25^\circ\text{C}$	I_{DSS}	—	—	-1.0	μA	$V_{DS} = -35V, V_{GS} = 0V$
Gate-Source Leakage	I_{GSS}	—	—	± 100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 8)						
Gate Threshold Voltage	$V_{GS(th)}$	-1.0	—	-3.0	V	$V_{DS} = V_{GS}, I_D = -250\mu A$
Static Drain-Source On-Resistance	$R_{DS(on)}$	—	30 40	45 65	m Ω	$V_{GS} = -10V, I_D = -6A$ $V_{GS} = -4.5V, I_D = -4A$
Forward Transfer Admittance	$ Y_{fs} $	—	8	—	S	$V_{DS} = -10V, I_D = -6A$
Diode Forward Voltage	V_{SD}	—	—	-1.2	V	$V_{GS} = 0V, I_S = -6A$
DYNAMIC CHARACTERISTICS (Note 9)						
Input Capacitance	C_{iss}	—	985.2	—	pF	$V_{DS} = -25V, V_{GS} = 0V,$ $f = 1.0\text{MHz}$
Output Capacitance	C_{oss}	—	90.6	—	pF	
Reverse Transfer Capacitance	C_{rss}	—	75.3	—	pF	
Gate Resistance	R_g	—	7.0	—	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1\text{MHz}$
Total Gate Charge ($V_{GS} = -10V$)	Q_g	—	19.2	—	nC	$V_{GS} = -10V, V_{DS} = -28V, I_D = -6A$ $V_{GS} = -4.5V, V_{DS} = -28V,$ $I_D = -6A$
Total Gate Charge ($V_{GS} = -4.5V$)	Q_g	—	9.5	—		
Gate-Source Charge	Q_{gs}	—	2.0	—		
Gate-Drain Charge	Q_{gd}	—	3.5	—		
Turn-On Delay Time	$t_{D(on)}$	—	5.2	—	ns	$V_{DS} = -18V, V_{GS} = -10V,$ $R_L = 18\Omega, R_G = 3.3\Omega,$ $I_D = -1A$
Turn-On Rise Time	t_r	—	4.8	—	ns	
Turn-Off Delay Time	$t_{D(off)}$	—	45.8	—	ns	
Turn-Off Fall Time	t_f	—	29.5	—	ns	

Notes: 8. Short duration pulse test used to minimize self-heating effect.
 9. Guaranteed by design. Not subject to product testing.

N-CHANNEL, Q1



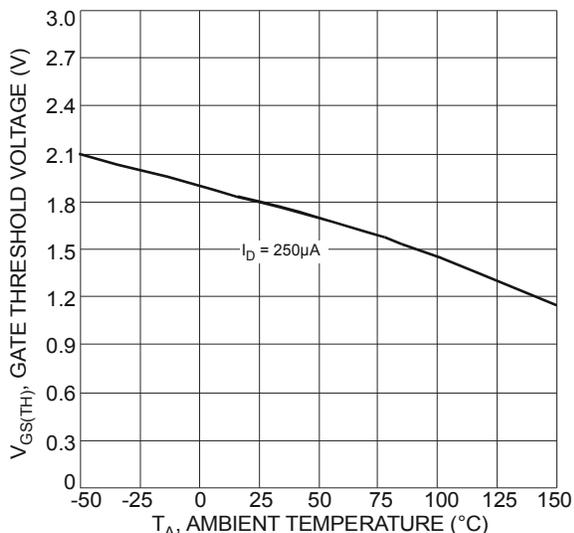


Fig. 7 Gate Threshold Variation vs. Ambient Temperature

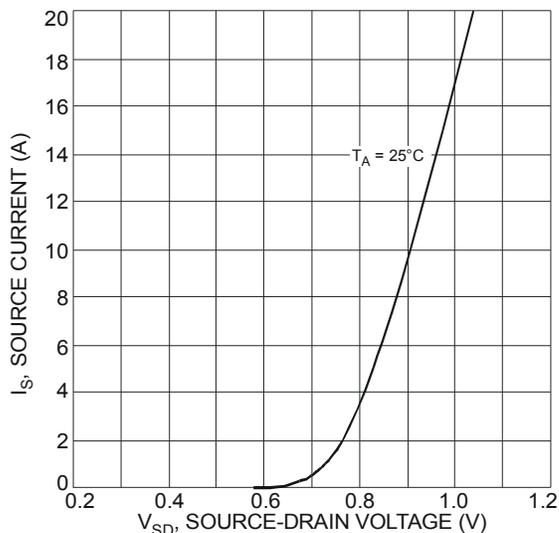


Fig. 8 Diode Forward Voltage vs. Current

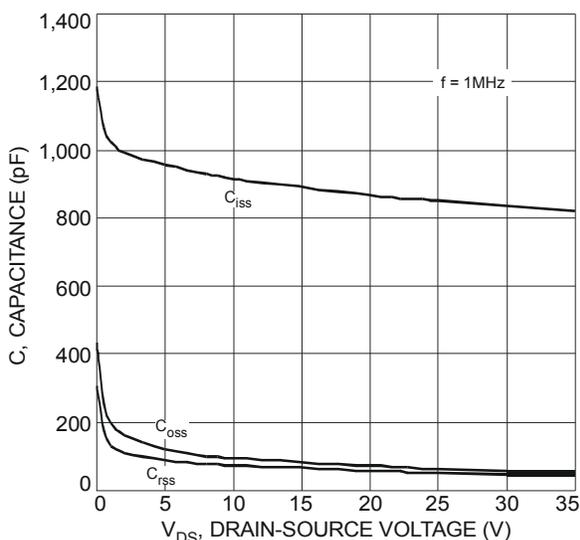


Fig. 9 Typical Total Capacitance

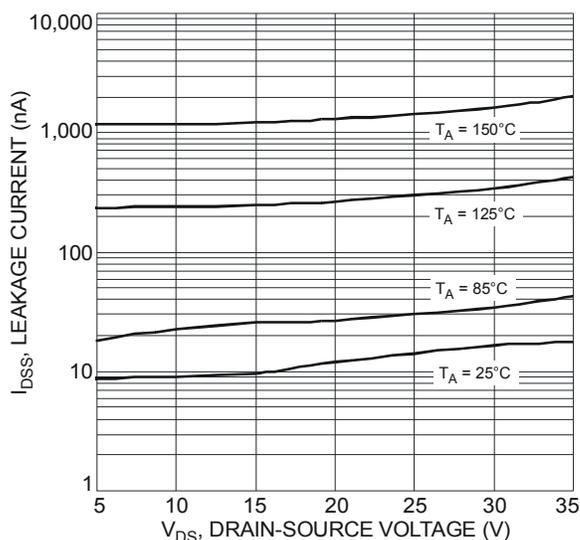


Fig. 10 Typical Leakage Current vs. Drain-Source Voltage

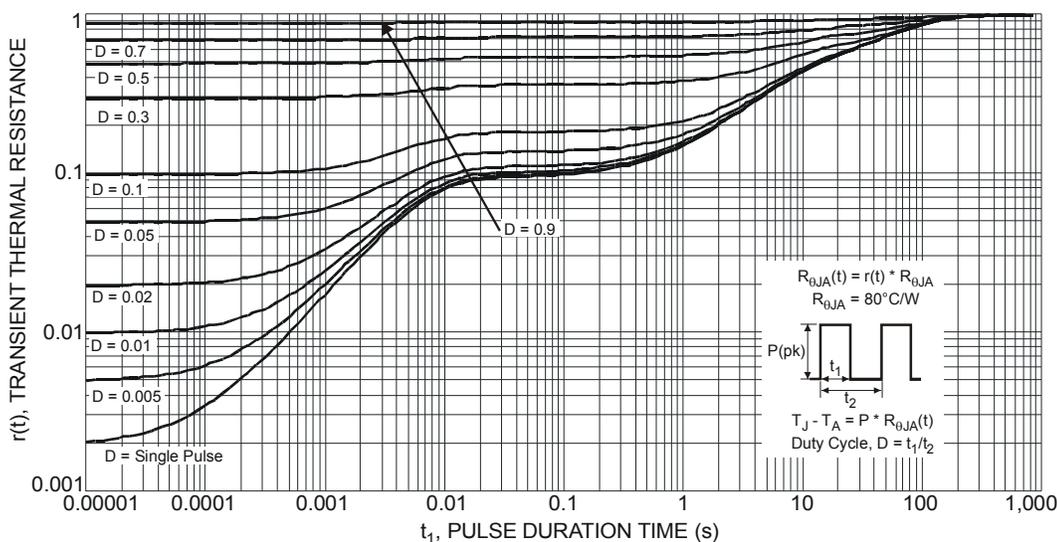
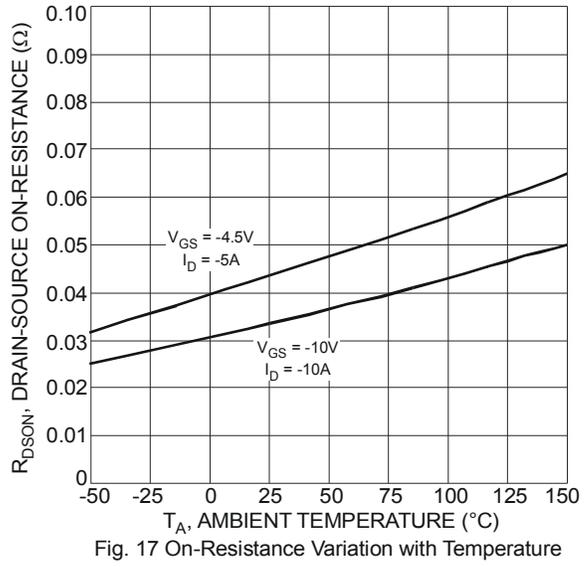
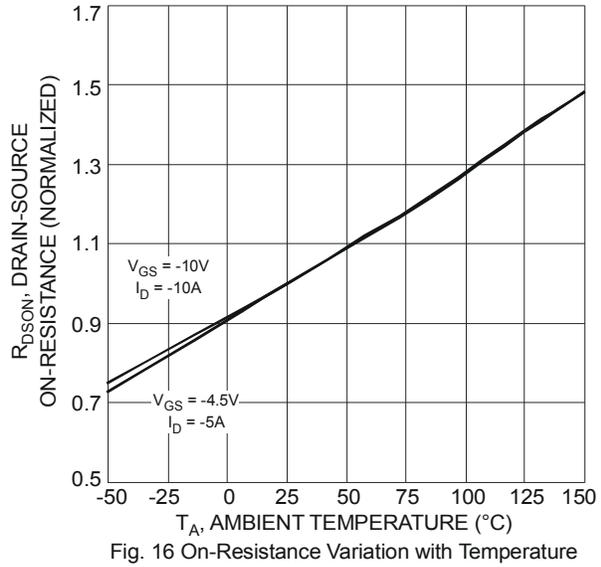
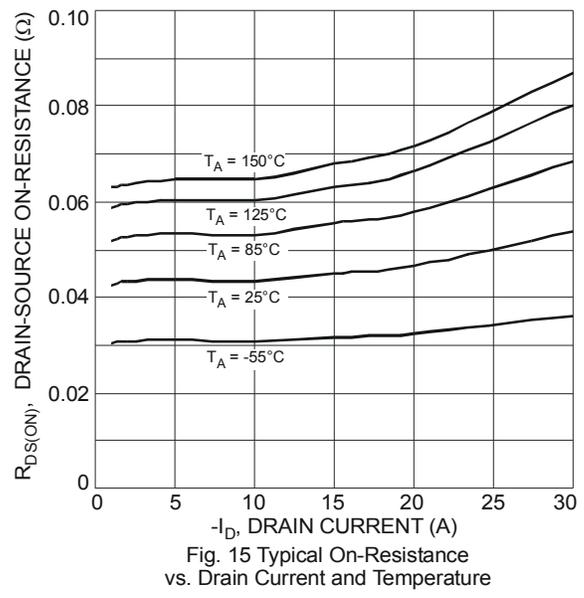
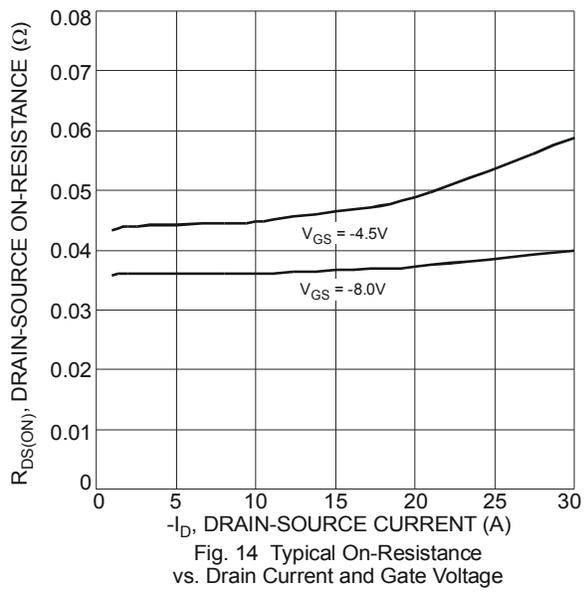
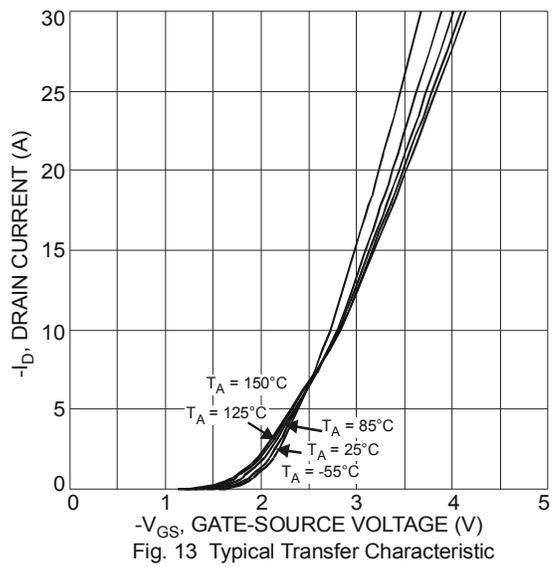
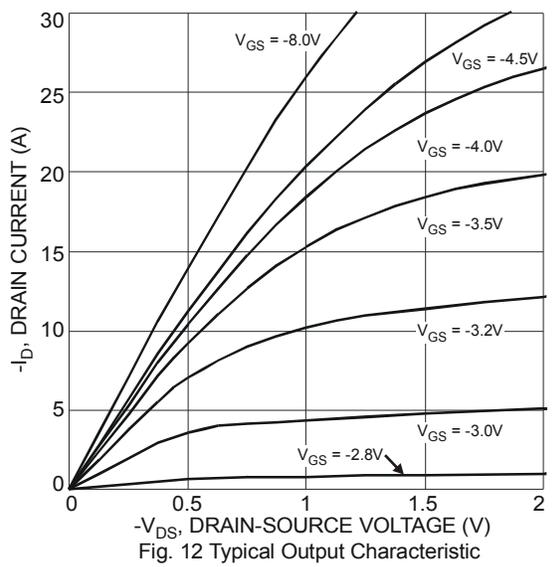


Fig. 11 Transient Thermal Response

P-CHANNEL, Q2



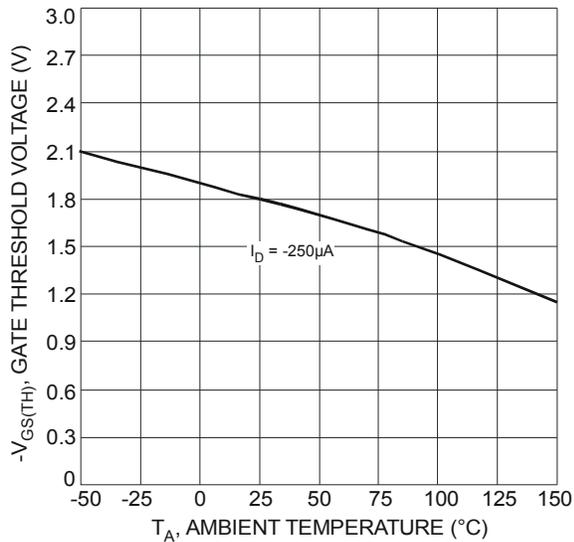


Fig. 18 Gate Threshold Variation vs. Ambient Temperature

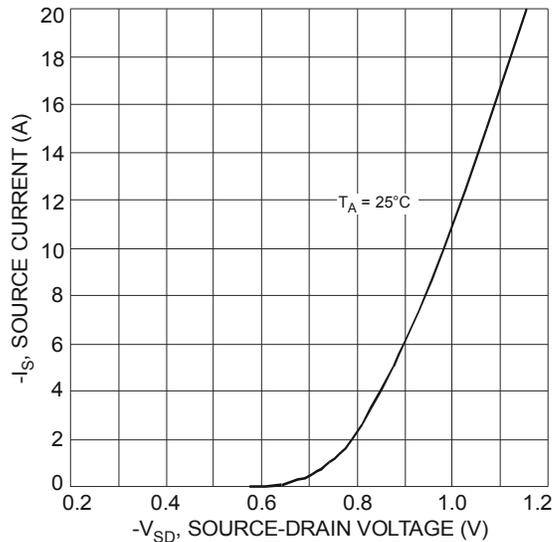


Fig. 19 Diode Forward Voltage vs. Current

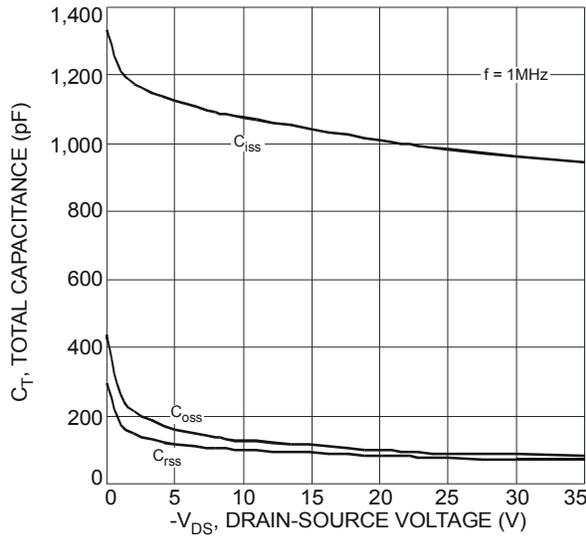


Fig. 20 Typical Total Capacitance

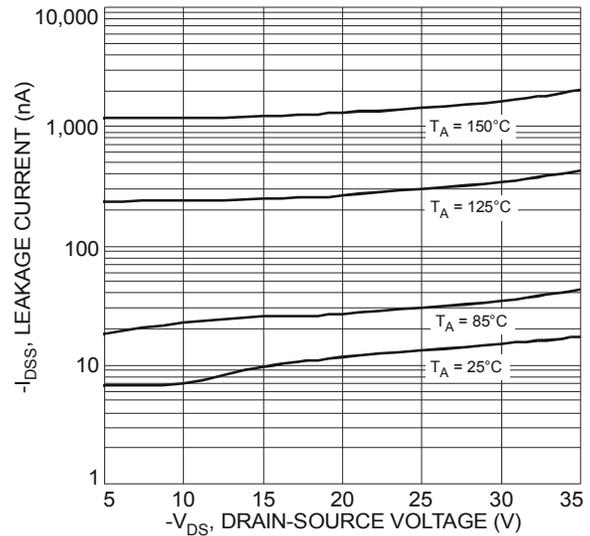


Fig. 21 Typical Leakage Current vs. Drain-Source Voltage

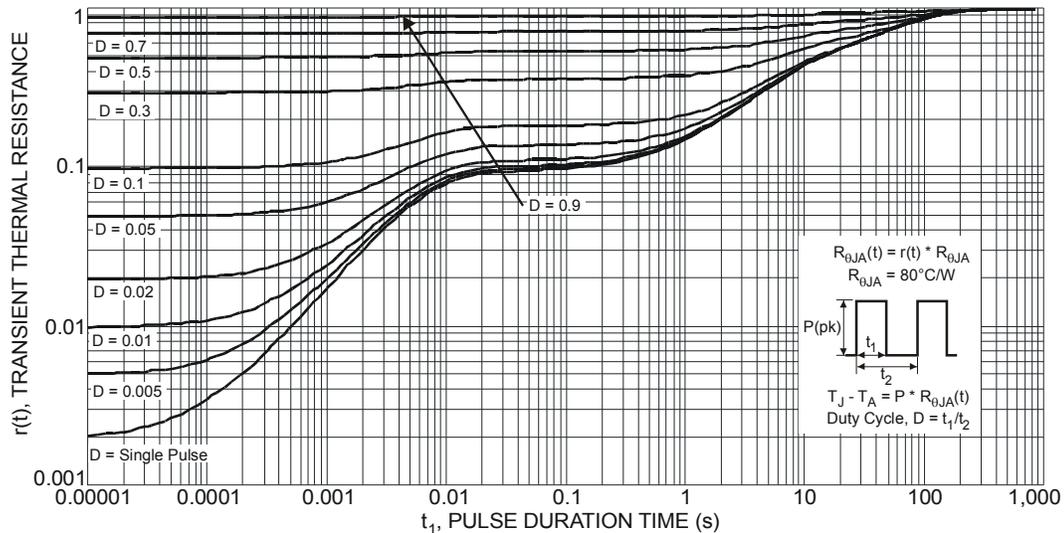
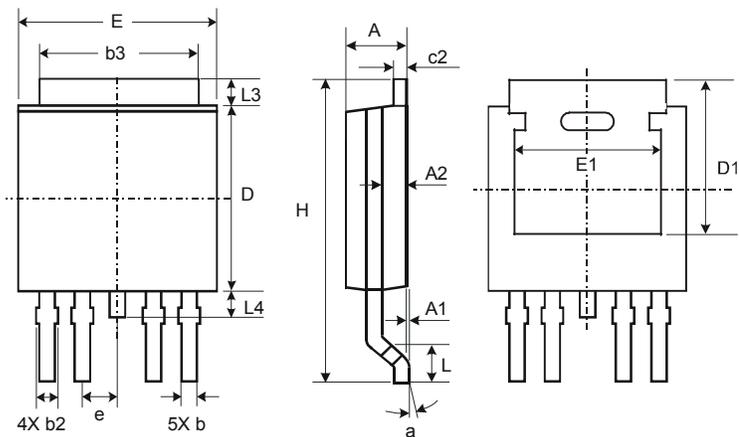


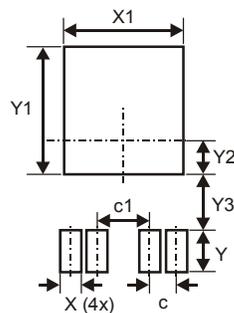
Fig. 22 Transient Thermal Response

Package Outline Dimensions



TO252-4L			
Dim	Min	Max	Typ
A	2.19	2.39	2.29
A1	0.00	0.13	0.08
A2	0.97	1.17	1.07
b	0.51	0.71	0.583
b2	0.61	0.79	0.70
b3	5.21	5.46	5.33
c2	0.45	0.58	0.531
D	6.00	6.20	6.10
D1	5.21	-	-
e	-	-	1.27
E	6.45	6.70	6.58
E1	4.32	-	-
H	9.40	10.41	9.91
L	1.40	1.78	1.59
L3	0.88	1.27	1.08
L4	0.64	1.02	0.83
a	0°	10°	-
All Dimensions in mm			

Suggested Pad Layout



Dimensions	Value (in mm)
c	1.27
c1	2.54
X	1.00
X1	5.73
Y	2.00
Y1	6.17
Y2	1.64
Y3	2.66